Form PTO 1449 (Modified)	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	ATTY DOCKET NO. 220102US2		SERIAL NO. NEW APPLICATION
		APPLICANT Masaaki ADACHI		
LIST OF REFERENCES CITED BY APPLICANT		FILING DATE HEREWITH		GROUP

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	AA						
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						
	AL						
	AM						
	AN						

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES	NO
	AO					
	AP					
	AQ					
	AR					
	AS					
	AT					
	AU					

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)

MH	AV	Akiko HARASAKI, et al., "IMPROVED VERTICAL-SCANNING INTERFEROMETRY", APPLIED OPTICS, Vol. 39, No. 13, 1 May 2000, pp. 2107-2115
MH	AW	Leslie DECK, et al., "HIGH-SPEED NONCONTACT PROFILER BASED ON SCANNING WHITE-LIGHT INTERFEROMETRY", APPLIED OPTICS, Vol. 33, No. 31, 1 November 1994, pp. 7334-7339
MH	AX	Yeou-Yen CHENG, et al., "TWO-WAVELENGTH PHASE SHIFTING INTERFEROMETRY", APPLIED OPTICS, Vol. 23, No. 24, 15 December 1984, pp. 4539-4543
MH	AY	Byron S. LEE, et al., "PROFILOMETRY WITH A COHERENCE SCANNING MICROSCOPE", APPLIED OPTICS, Vol. 29, No. 26, 10 September 1990, pp. 3784-3788
UM	AZ	Masaaki ADACHI, et al., "HOW TO ATTAIN HIGH-SPEED SCANNING IN A VERTICAL SCAN TYPE WHITE LIGHT INTERFERENCE METHOD", a treatise collection distributed at a meeting of the Japan Association for Precision Engineering, 5 March 2001 ☐ Additional References sheet(s) attached

Examiner	Date Considered July 24, 2003

*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.